

**Search Notes**

Application/Control No.

10/626,693

Examiner

Madeleine AV Nguyen

Applicant(s)/Patent under  
Reexamination

MEYER, JOHN F.

Art Unit

2625

**SEARCHED**

| Class  | Subclass | Date      | Examiner |
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| update |          | 10/3/2007 | AV       |
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**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

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